

Express Mail No. EV 313 841 775 US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

RECEIVED

Application of:

Conant et al.

Confirmation No.:

1213

SEP 2 9 2003

Serial No.:

10/076,296

Art Unit:

1765

TC 1700

Filed:

February 13, 2002

Examiner: ALANKO, ANITA KAREN

For:

STAGGARD TORSIONAL

Attorney Docket No.:

9840-0068-999

ELECTROSTACTIC COMBDRIVE AND METHOD OF FORMING **SAME**

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure provisions of 37 C.F.R. §1.56, there is hereby provided certain information which the Examiner may consider material to the examination of the subject U.S. patent application. It is requested that the Examiner make this information of record if it is deemed material to the examination of the application.

		••					
1.	Enclos	Enclosures accompanying this Information Disclosure Statement are:					
	la.	A list of all patents, publications, applications, or other information submitted for consideration by the office.					
	1b.	A legible copy of:					
		Each U.S. patent application publication and U.S. and foreign patent;					
		☐ Each publication or that portion which caused it to be listed on the PTO-1449;					
		For each cited pending U.S. application, the application specification including the claims, and any drawing of the application, or portion of the application which caused it to be listed on the PTO-1449 including any claims directed to that portion;					
		all other information or portion which caused it to be listed on the PTO-1449.					
	1c.	An English language copy of search report(s) from a counterpart foreign application or PCT International Search Report.					
	1d.	Explanations of relevancy (ATTACHMENT 1(d), hereto) or English language abstracts of the non-English language publications.					
2.		This Information Disclosure Statement is filed under 37 C.F.R. §1.97(b): Within three months of the filing date of a national application other than a continued prosecution application under §1.53(d):					

01,	m	•							
SEP 1 9 20	10 (S.)	Within three months of the date of entry of the national stage as set forth in §1.491 in an international application;							
MANA		Before the mailing of the first Office action on the merits;							
		Before the mailing of a first Office action after the filing of a request for continued examination under §1.114.							
3.	\boxtimes	This Information Disclosure Statement is filed under 37 C.F.R. §1.97(c) after the period specified in 37 C.F.R §1.97(b), but before the mailing date of any of a final action under 37 C.F.R. §1.113, a notice of allowance under 37 C.F.R. §1.311 or an action that otherwise closes prosecution in the application.							
		(Check either Item 3a or 3b)							
	3a.	☐ The Certification Statement in Item 5 below is applicable. Accordingly, no fee is required.							
	3b.	 ☑ The \$180.00 fee set forth in 37 C.F.R. §1.17(p) in accordance with 37 C.F.R. §1.97(c) is: ☑ enclosed ☑ to be charged to Pennie & Edmonds LLP Deposit Account No. 16-1150. 							
		(Item 3b to be checked if any reference known for more than 3 months)							
4.		This Information Disclosure Statement is filed under 37 C.F.R. §1.97(d) after the period specified in 37 C.F.R. §1.97(c), but on or before the date of payment of the issue fee.							
		The \$180.00 fee set forth in 37 C.F.R. §1.17(p) is: enclosed. to be charged to Pennie & Edmonds LLP Deposit Account No. 16-1150.							
	The C	The Certification Statement in Item 5 below is applicable.							
5.		Certification Statement (applicable if Item 3a or Item 4 is checked)							
		(Check either Item 5a or 5b)							
	5a.	In accordance with 37 C.F.R. §1.97(e)(1), it is certified that each item of information contained in this Information Disclosure Statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement.							
	5b.	Each item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart application, and the communication was not received by any individual designated in 37 C.F.R. §1.56(c) more than thirty days prior to the filing of this information disclosure statement.							
	5c.	Pursuant to 37 C.F.R. §1.704(d), each item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart application, and the communication was not received by any individual designated in 37 C.F.R. §1.56(c) more than thirty days prior to the filing of this information disclosure statement.							

100	<u>``</u>				
\$ 19 m	3				
T. W. F. MACK CES		\square	This application is a divisi or (d).	onal application under 37 C.F.R. §1.60 or §1.53	(b)
			(Check appro	priate Items 6a, 6b and/or 6c)	
		6a.	A Petition to Withdray filed herewith.	v from issue under 37 C.F.R. §1.313(b)(5) is con	ncurrently
		6b.	No. 09/584,835, filed	listed on Form PTO-1449 from prior application May 31, 2000, of which this application clair are not being submitted pursuant to 37 C.F.R. §	ns priority
		6c.	Copies of the publicate prior application Seria	ons listed on Form PTO-1449 were not previou l No. , filed on , and are provided h	
. 7			This is a Supplemental Inf	ormation Disclosure Statement. (Check Item 7a	ι)
		7a.	supplements the Informattempt was made to commerce made. These omadditional time is requ	ormation Disclosure Statement under 37 C.F.R. mation Disclosure Statement filed on A bomply with 37 C.F.R. §1.98, but inadvertent omissions have been corrected herein. Accordinglested so that this Supplemental Information Disidered as if properly filed on	oona fide nissions y,
				R. §1.98, a concise explanation of what is presented of each non-English language publication is	
			(Che	eck Item 8a, 8b, or 8c)	
		8a.	enclosed English langu	on-English language publications were cited on age copy of the PCT International Search Repopunterpart foreign application indicating the dege foreign office.	ort or the
		8b.	set forth in the applica	tion.	
		8c.	enclosed as an attachn	nent hereto.	
. 9).	\boxtimes		orized to charge any additional fee required or comation Disclosure Statement and/or Petition to Ecount No. 16-1150.	
1	0.		to be, material to patentabi than a search report of a fo	the information cited in this Statement is, or is lity nor a representation that a search has been region counterpart application or PCT Internation (th). 37 C.F.R. §§1.97(g) and (h).	made (other
				Respectfully submitted,	
Γ	Date:	Senter	nber 19, 2003	As 16/1/2	31,066
ı	- 4.0.	Septer		Gary S. Williams PENNIE & EDMONDS LLP 3300 Hillview Avenue Palo Alto, California 94304 (650) 493-4935	(Reg. No.)

× 0/3											
SEP 10		-	. -				Sheet 1 of				
LIST OF REFERENCES CITED BY APPLICANT				ATTY DOCKET NO 9840-0068-999			APPLICATION NO 10/076,296 PECE. SEP 25 GROUP TC 170				
										LIST OF RE	FERENCES CITED BY (Use several sheets if r
	(,		Conant et al.			~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~				
				FILING DATE February 13, 20	02	1765	/C 1>				
		U.S. PATE	NT DOCUM	ENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	. N.	AME	CLASS	SUBCLASS	FILING DAT				
							-				
		FOREIGN PA	TENT DOC	UMENTS							
	DOCUMENT NUMBER	DATE	COL	INTRY	CLASS	SUBCLASS	TRANSLATI				
							YES Y				
······································					· · · · · · · · · · · · · · · · · · ·						
	:										
	OTHER REFERE	NCFS (Includin	a Author Tit	la Data Partinan	t Pages	Etc.)	<u></u> .				
,											
	Conant et al. "Cyclic Fatigue Testing of Surface-Micromachined Thermal Actuators", 1998 ASM Mechanical Engineering Congress and Exposition, Nov. 15-20, 1998, Anaheim, CA DSC-Vol. 6	Vol. 66, pp.									
	Cotton et al., "Wide-angle geocornal telescope: a He-II 304-A plasmaspheric imager", Optical Engineering, December 1993, Vol. 32 No. 12, pages 3170-3173										
	Hart et al., "Stroboscopic phase-shifting interferometry for dynamic characterization of optical MEMS", 18th Congress of the International Commission for Optics, ICO XVIII August 2-6, 1999, San Francisco, CA USA, Optics										
	for the Next Millennium	, Technical Digest S	SPIE Volume 3	749, pgs 468-469							
	Hoon et al, "A Model for SIMOX Buried-Oxide High-Field Conduction", IEEE Transactions on Electron Devices, Vol. 43, No. 11, November 1996										
	Hyodo et al., "An HDR System Hydraulics Model and Detailed Analysis of the 1991 Circulation Test at the Hijiori HDR Site, Japan", Geothermal Resources Council Transactions, Vol. 198, October 1995, pgs 263-268										
	Hyodo et al., "An HDR System Hydraulics Model and Analysis of the 1995 Preliminary Circulation Test at the Hijiori HDR Site of the NEDO Project, Japan", Twentieth Stanford Workshop on Geothermal Reservoir Engineering, pgs 23-										
	24										
	Wright et al., "Hydraulic Fracture Orientation and Production/Injection Induced Reservoir Stress Changes in Diatomite Waterfloods", Society of Petroleum Engineers, pages 139-151 Wright et al., "Reorientation of propped refracture treatments", Eurock '97 € 1994 Balkema, Rotterdam, ISBN 90										
	Wright et al., "Reorienta 5410 502 X, pages 417-		acture treatmen	ts", Eurock '97 🤄 1	994 Balker	na, Rotterdai	n, ISBN 90				
	Yap et al., "Conduction l	Mechanisms Throug			dings of 19	93 IEEE Inte	ernational SO				
	Yap et al. "A Model for	Conference, Palm Springsm, CA, USA, October 5-7, 1993, pp. 32-33 Yap et al. "A Model for High-Field Conduction In Simox Buried Oxides", in Proceedings of 1994 IEEE International									
	Yao and MacDonald, "S	ingle Crystal Silicor	SA, October 5-7, 1993, pp. 32-33								
-	36(5):1408-1413, May 1 Yeh et al., "Integrated Po	olysilicon and DRIE			an Electros	tatic Torsion	al Actuator",				
	Microelectromechanical Systems, 8(4):456-465, Dec. 1999 Yeh et al. "Mechanical Digital-To-Analog Converters", proc. Transducers '99, Sendai, Japan, June 1999, pp. 998-										
	Yoon et al. "Use of High					dings of 199	5 IEEE				
	International SOI Confer	rence, Tucson, AZ,	LSA, October .	5-5, 1995, pp. 146-1	+ /						
EXAMINER			DATE C	ONSIDERED							

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.